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Commissioner for Patents, P.O. Box 1450, Alexandria VA, 22313-1450.

*Aug 22*

Signature

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AUG 17 2004

OFFICE OF PETITIONS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:  
Tongbi Jiang and Zhiqiang Wu

Assignee: Micron Technology

Serial No.: 09/740,751

Filed: December 19, 2000

Title: Method for Forming Novel Zero Force  
Insertion Sockets Using Negative Thermal  
Expansion Materials (*as amended  
previously*)

Group Art Unit: 3729

Examiner: Rick K. Chang

Examiner phone: (703) 308-4784

Atty. Dkt. No.: 102-0118US2

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AUG 18 2004  
TECHNOLOGY CENTER H3700*

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria VA, 22313-1450.

Sir:

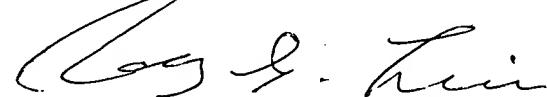
In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement (IDS) be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed documents are attached.

In accordance with 37 C.F.R §§ 1.97(g),(h), this IDS is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that the information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b), or that such information constitutes prior art.

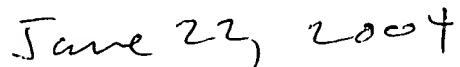
This IDS is being filed prior to the receipt of a first Official Action reflecting an examination on the merits, and hence is believed to be timely filed in accordance with 37 C.F.R § 1.97(b). No fees are believed to be due in connection with the filing of this IDS. However, the Commissioner is authorized to deduct any necessary fees from Deposit Account No. 501922, referencing matter no. 102-0118US-2.

Applicant respectfully requests that the listed documents be considered and made of record in the present case, and that the Examiner initial the appropriate spaces on the Form 1449 to evidence the same

Respectfully submitted,



Terril G. Lewis, Reg. No. 46,065



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Form PTO-1449 (modified)

Atty. Docket No.  
102-0118US2Serial No.  
09/740,751List of Patents and Publications for Applicant's  
INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Inventor/Applicant:  
Tongbi Jiang et al. / Micron Technology, Inc.Title: Method for Forming Novel Zero Force  
Insertion Sockets Using Negative Thermal  
Expansion Materials (as amended previously)Filing Date:  
12/19/00Group:  
3729

## U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
	A1	4,513,055	Apr. 23, 1985	Leibowitz	428	245	
	A2	6,274,932	Aug. 14, 2001	Mikagi	257	754	
	A3	6,187,700	Feb. 13, 2001	Merkel	501	32	
	A4	5,497,545	Mar. 12, 1996	Watanabe et al.	29	830	
	A5	5,919,720	Jul. 6, 1999	Sleight et al.	501	126	
	A6	5,641,291	Jun. 24, 1997	Sueki et al.	439	83	
	A7	4,950,173	Aug. 21, 1990	Minemura et al.	439	82	
	A8	5,607,313	Mar. 4, 1997	Nyman	439	83	
	A9	5,123,849	Jun. 23, 1992	Deak et al.	439	66	
	A10	5,387,121	Feb. 7, 1995	Kurz	439	342	
	A11	5,433,778	Jul. 18, 1995	Sleight	106	401	
	A12	5,514,360	May 7, 1996	Sleight et al.	423	593	
	A13	5,466,169	Nov. 14, 1995	Lai	439	264	

## Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						

## Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	T.A. Mary et al., "Negative Thermal Expansion from 0.3 to 1050 Kelvin in ZrW <sub>2</sub> O <sub>8</sub> ," <i>Science</i> , Vol. 272, pp. 91-93 (Apr. 5 1996).
	C2	Anonymous, "Seimens Demonstrates Fingertip Chip Sensor," <i>Semiconductor International</i> , pp. 33-34 (Apr. 1998).

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.